## SEMATECH Workshop on Nanoparticle Defectivity Issues in Solutions 2013

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July 9, 2013 San Francisco, CA

Agenda	SEMATECH
Nucleation of Trace Elements in DI-water Heating Systems 1	Uwe Dietze, SUSS MicroTec
Approaches to Reduce Defectivity in Process Chemistries 30	Jennifer Braggin, Entegris
Technique for Measuring the Particle Retention of Liquid Filters to 10 nanometers 45	Gary Van Schooneveld/Don Grant/Mark Litchy, CT Associates
Nanodefect Center Overview 73	Mike Lercel, SEMATECH
Nano Particle Defectivity Monitoring using an Inspection Tool 93	Nano Particle Defectivity Monitoring using an Inspection Tool, KLA-Tencor
Comparison of Particle Shedding of High Purity Pumps 110	Mark Litchy/Juergen Hahn, CT Associates/Levitronix GmbH
Challenges of Sub-50 Nanometer Particle Detection in High Purity Water Applications 136	Michael Thomas, Lighthouse Worldwide Solutions
Interaction Between Process Requirements and Ultrapure Water/Chemical Purity  Level 156	Slava Libman/Drew Sinha/Andreas Neuber, Air Liquide/Siltronic AG/Applied Materials
Control and Measurement of Liquid-borne Particles in High Volume Process Chemicals 173	Wayne McDermott/Michael Cali, Air Products
2013 Workshop on Nanoparticle Defectivity Issues in Soltuions-Sumary 200	SEMATECH